Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/820,023	HAN, JAE MYUNG
	Examiner	Art Unit
	Chuck Mah	3677

SEARCHED			
Class	Subclass	Date	Examiner
16	273 X		
	277		
	281		
	286 X		
	80		
	70		
	50		
	374		
	375		
	319		
312	401		
	405		
	325-326		
	329		
	319.2		
49	399		
	109	9/27/05	eg
	Updated	5/3/06	MM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
16	all		
	above	3/8/07	eg

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR